

• General Description

This silicon carbide Power MOSFET device has been developed using ZMJ's advanced 1st generation SiC MOSFET technology. The device features a very low RDS(on) over the entire temperature range combined with low capacitances and very high switching operations. It improves application performance in frequency, energy efficiency, system size and weight reduction.

• Features

- High Blocking Voltage
- High Speed Switching With Low Capacitances
- Low $R_{DS(ON)}$ to Minimize Conductive Loss
- Low Gate Charge For Fast Switching
- Low Thermal Resistance
- AEC-Q101 Qualified

• Application

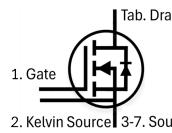
- Motor Drives
- On Board Charger
- DC-DC
- Auxiliary Drives

• Ordering Information:

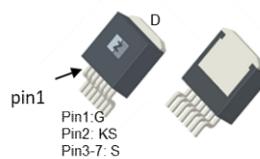
Part NO.	ZMCA100KR170B7				
Marking	ZMC100KR170				
Packing Information	REEL TAPE				
Basic ordering unit (pcs)	1000				

• Absolute Maximum Ratings ($T_A=25^\circ\text{C}$, unless otherwise specified)

Parameter	Symbol	Conditions	Min.	Max.	Unit
Drain-Source Voltage	V_{DS}		-	1700	V
Gate-Source Voltage ^①	V_{GS}	Transient Voltage	-10	25	V
	V_{GS}	Static Voltage	-10	24	V
Recommended turn on gate voltage	$V_{GS(on)}$		15	18	V
Recommended turn off gate voltage	$V_{GS(off)}$		-4	0	V
Continuous Drain Current	I_D	$V_{GS}=18\text{V}, T_C=25^\circ\text{C}$	-	5.9	A
	I_D	$V_{GS}=18\text{V}, T_C=75^\circ\text{C}$	-	4.8	A
	I_D	$V_{GS}=18\text{V}, T_C=100^\circ\text{C}$	-	4.2	A
Pulsed Drain Current ^①	I_{DM}	Pulsed; $t_p \leq 10\ \mu\text{s}; T_C = 25^\circ\text{C}$	-	23.6	A
Total Power Dissipation	P_D	$T_C=25^\circ\text{C}$	-	56	W
Total Power Dissipation	P_D	$T_A=25^\circ\text{C}$	-	2.4	W
Operating Junction Temperature	T_J		-55	175	°C
Storage Temperature	T_{STG}		-55	175	°C
ESD Level (HBM)			CLASS 1C		



$V_{DS} = 1700\text{V}$
 $R_{DS(ON)} = 750\text{m}\Omega$
 $I_D = 5.9\text{A}$



TO-263-7



•Thermal resistance

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal resistance, junction - case	R _{thJC}	-	-	2.7	°C/W
Thermal resistance, junction-ambient	R _{thJA} ^②	-	-	62	°C/W
Soldering temperature	T _{sold}	-	-	260	°C

•Electronic Characteristics (T_j=25°C,unless otherwise specified)

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V, I _D =250uA	1700	-	-	V
Gate Threshold Voltage	V _{GS(TH)}	V _{GS} =V _{DS} , I _D =1mA	3	4	5	V
Drain-Source Leakage Current	I _{DSS}	V _{GS} =0V, V _{DS} =1700V	-	-	10	uA
Gate- Source Leakage Current	I _{GSS}	V _{GS} =-10V, V _{DS} =0V	-	-	-100	nA
	I _{GSS}	V _{GS} =25V, V _{DS} =0V	-	-	100	nA
Static Drain-source On Resistance	R _{DS(ON)}	V _{GS} =18V, I _D =2A, T _j =25°C	-	750	900	mΩ
		V _{GS} =18V, I _D =2A, T _j =175°C	-	1327	-	mΩ
		V _{GS} =15V, I _D =1A, T _j =25°C	-	980	-	mΩ
Forward Transconductance	g _{FS}	V _{DS} =20V, I _{SD} =2A	-	1.3	-	S
Diode Forward Voltage	V _{FSD}	V _{GS} =-4V,I _{SD} =2A	-	3.9	5	V

•Dynamic characteristics (T_j=25°C,unless otherwise specified)

Parameter	Symbol	Condition	Min.	Typ.	Max.	Unit
Input capacitance	C _{iss}	f = 100KHz, V _{DS} =1000V, V _{GS} =0V	-	165	-	pF
Output capacitance	C _{oss}		-	13.4	-	
Reverse transfer capacitance	C _{rss}		-	2.4	-	
Output Charge	Q _{oss}	f = 100KHz,V _{GS} =0V, V _{DS} =0V to 1000V	-	21.4	-	nC
Coss Stored Energy	E _{oss}		-	7.8	-	uJ
Gate Resistance	R _g	f = 1MHz	-	25	-	Ω
Total gate charge	Q _g	V _{DD} = 1200V,I _D = 2A, V _{GS} = -4V/18V	-	15.5	-	nC
Gate - Source charge	Q _{gs}		-	2.8	-	
Gate - Drain charge	Q _{gd}		-	9.9	-	
Turn-ON Delay time	t _{D(on)}	V _{GS} =-4V/18V,V _{DS} =1200V,R _G =10Ω, I _D =2A	-	5	-	ns
Turn-ON Rise time	t _r		-	18	-	ns
Turn-Off Delay time	t _{D(off)}		-	13	-	ns
Turn-Off Fall time	t _f		-	59	-	ns
Turn-On Energy	E _{on}		-	83	-	uJ
Turn-Off Energy	E _{off}		-	13	-	uJ
Reverse Recovery Time	t _{rr}	V _{DD} =1200V, dI _S /dt = 1000A/us, I _S =2A	-	28	-	ns
Reverse Recovery Charge	Q _{rr}		-	29	-	nC

Fig.1 Gate-source voltage as a function of gate charge;Typical values;T_j=25°C

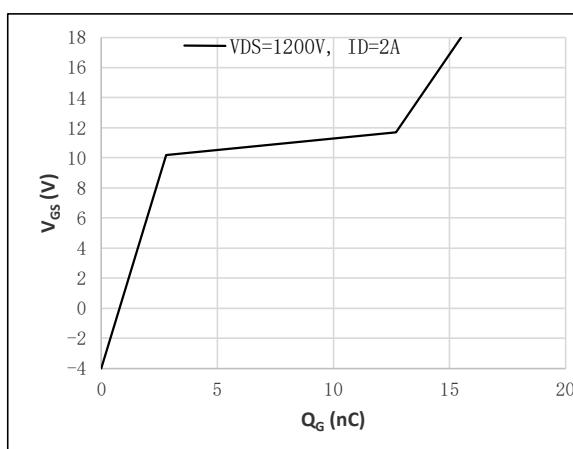


Fig.2 Input, output and reverse transfer capacitances as a function of drain-source voltage;Typical values;T_j=25°C

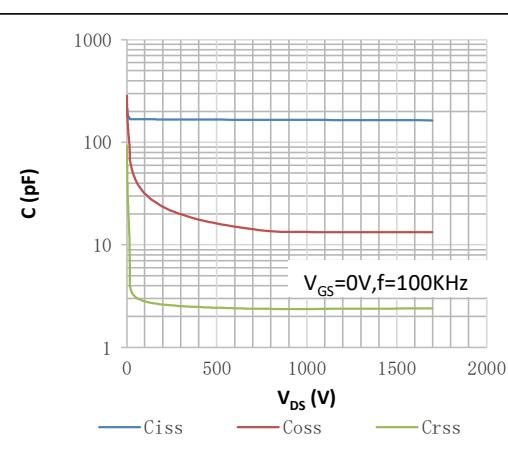


Fig.3 Output characteristics: drain current as a function of drain-source voltage;Typical values;T_j=25°C

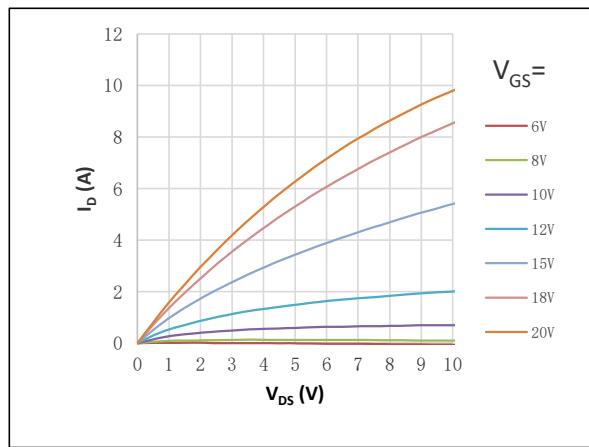


Fig.4 Output characteristics: drain current as a function of drain-source voltage;Typical values;Expanded curve;T_j=25°C

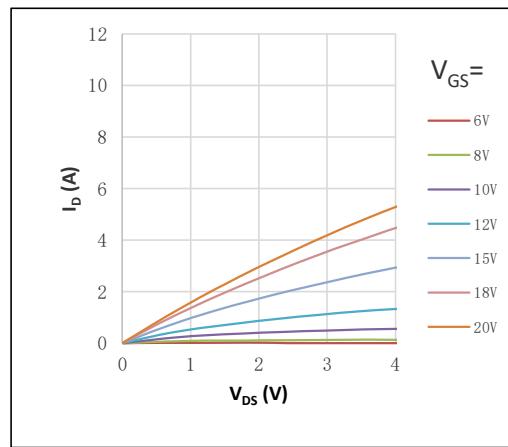


Fig.5 Gate-source threshold voltage as a function of junction temperature;Typical values

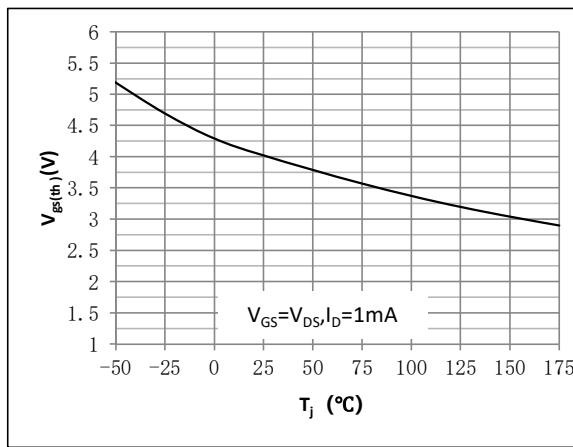


Fig.6 Drain-source on-state resistance as a function of drain current;Typical values;T_j=25°C

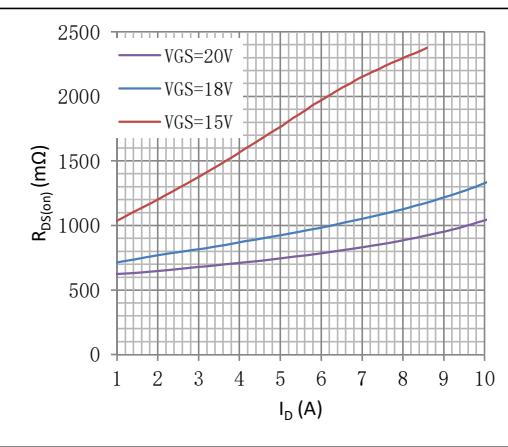


Fig.7 Drain-source on-state resistance as a function of gate-source voltage;Typical values

Fig.8 Normalized drain-source on-state resistance factor as a function of junction temperature;Typical values
Normalized On-Resistance=RDSon/RDSon(25°C)

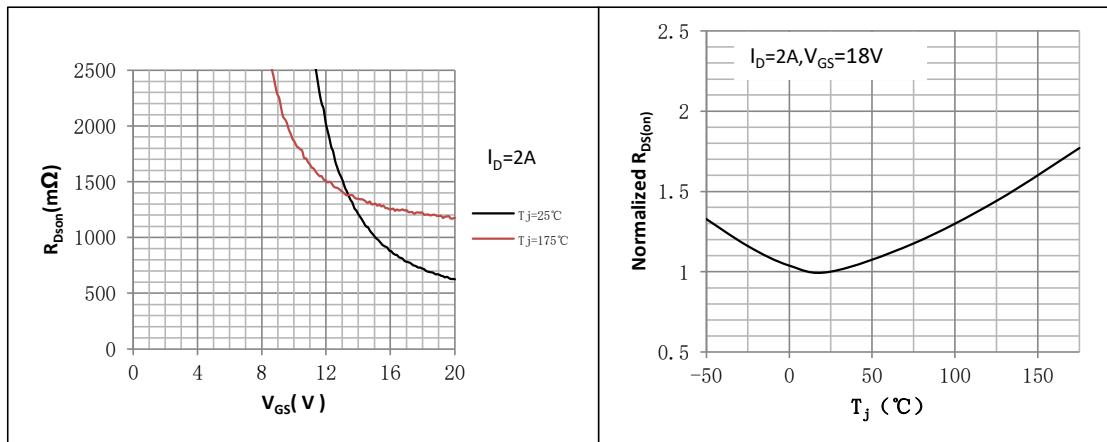


Figure 9. Source (diode forward) current as a function of source-drain (diode forward) voltage ;Typical values

Figure 10. Transfer characteristics: drain current as a function of gate-source voltage;Typical values

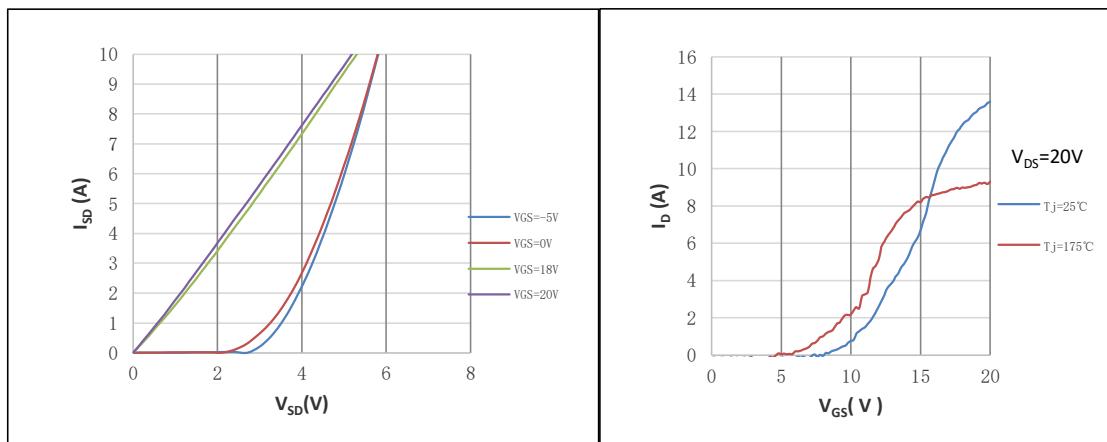


Fig.11 Safe operating area: continuous and peak drain currents as a function of drain-source voltage;Calculative values

Fig.12 Continuous drain current as a function of case temperature θ_c ;Calculative values

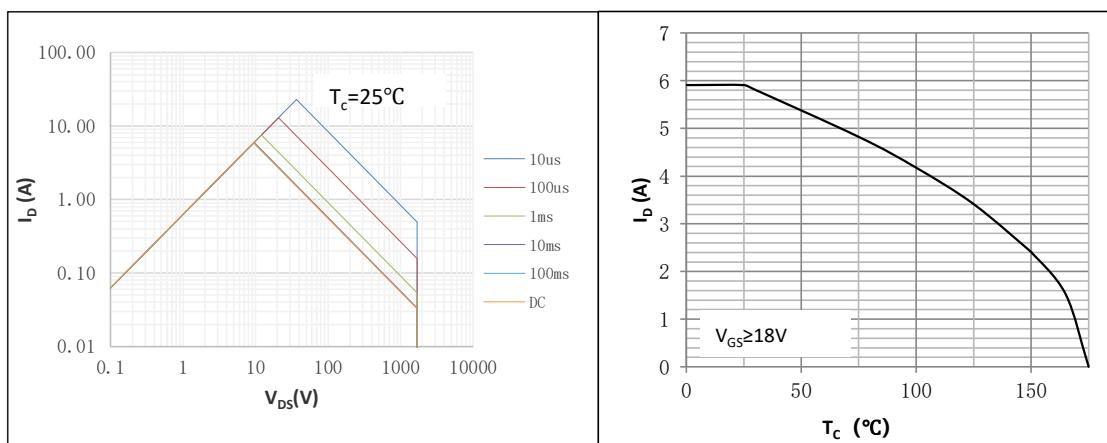


Fig.13 Drain-source breakdown voltage as a function of junction temperature;Typical values
Normalized $BVDSS = BVDSS/BVDSS(25^\circ C)$

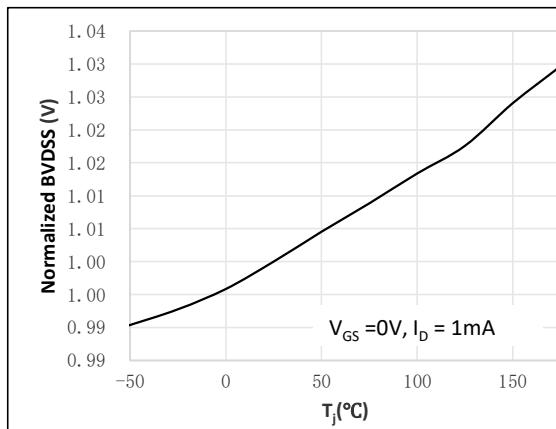


Fig.14 Normalized total power dissipation as a function of case temperature;Calculative values
Normalized Power Dissipation= $P_d/P_d(25^\circ C)$

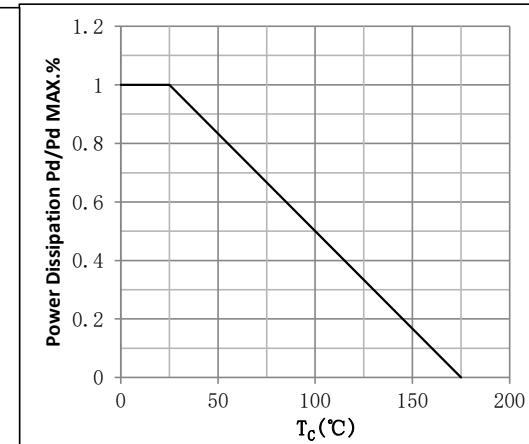


Fig.15 Transient thermal impedance from junction to case as a function of pulse duration; max values

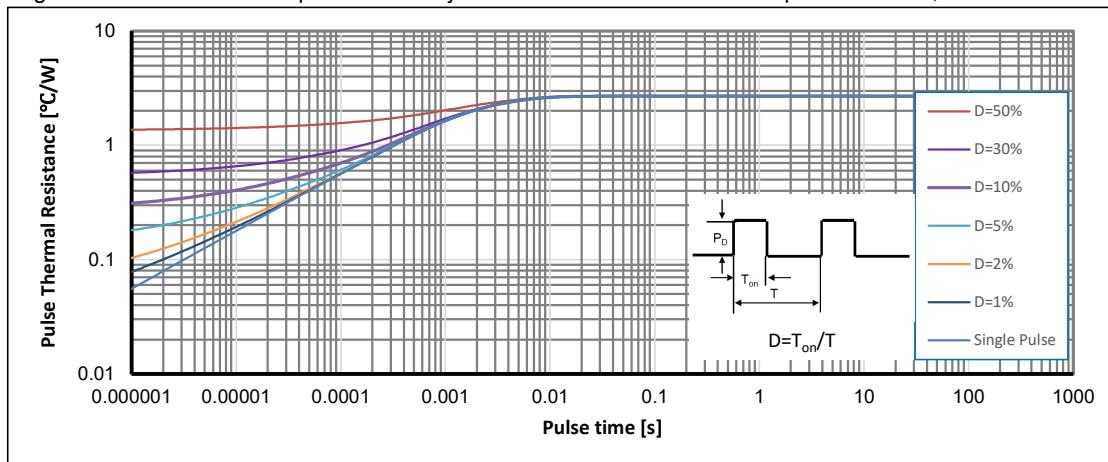
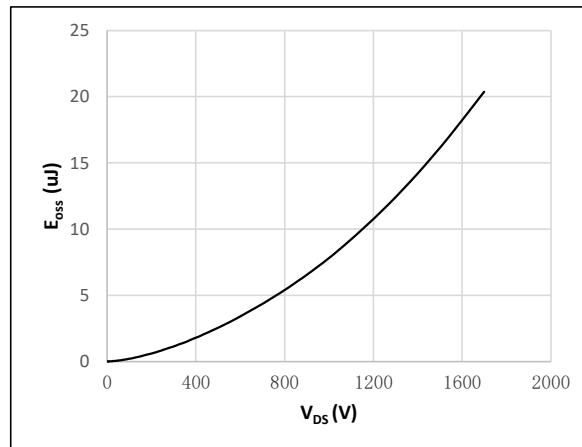
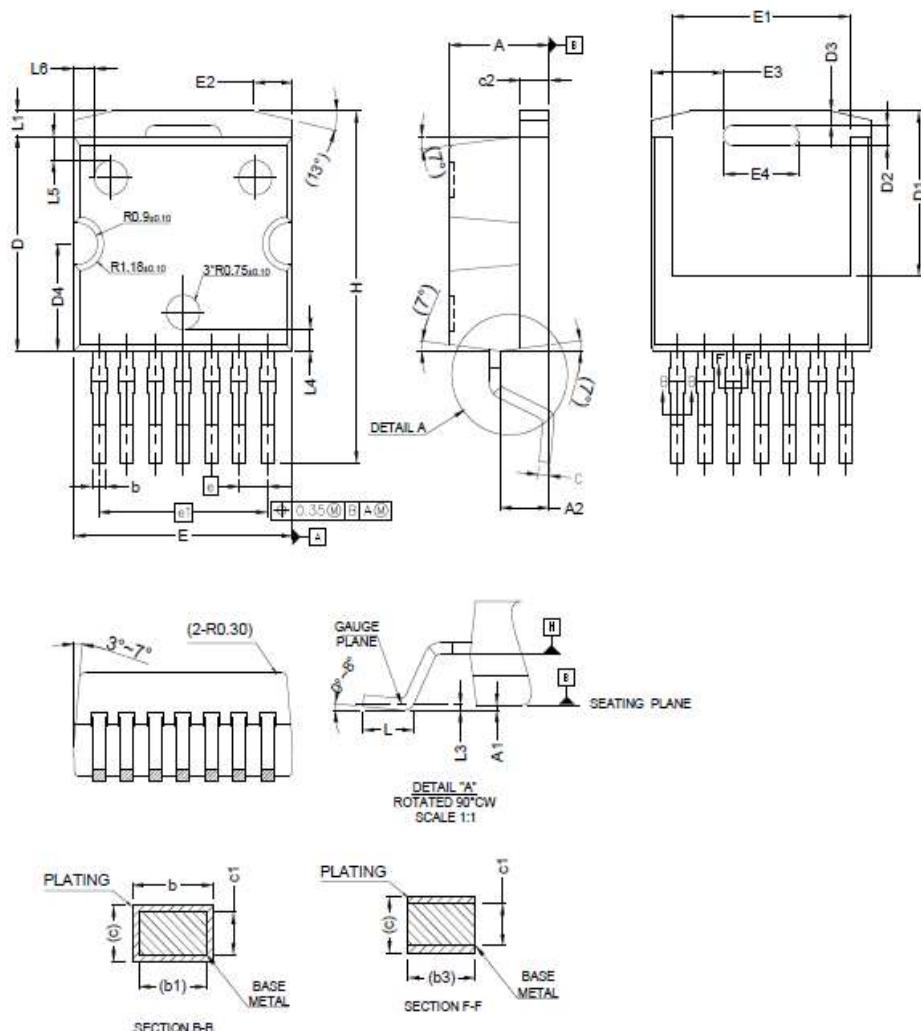


Fig.16 Output capacitor stored energy as a function of drain-source voltage;Typical values;
 $T_j=25^\circ C$



•TO-263-7 Package Outline



SYMBOL	MIN	MAX	SYMBOL	MIN	MAX
A	4.30	4.70	L	1.78	2.79
A1	-	0.25	L1	-	1.60
A2	2.02	2.42	L3	0.25BSC	
b	0.50	0.70	L4	0.93BSC	
b1	0.50	0.65	L5	1.04BSC	
b3	0.60	0.75	L6	0.93BSC	
c	0.45	0.60	H	14.61	15.88
c1	0.45	0.55			
c2	1.25	1.40			
D	9.10	9.50			
D1	6.86	7.42			
D2	0.72	1.12			
D3	0.40	0.80			
D4	4.45	4.85			
E	9.68	10.08			
E1	7.70	8.30			
E2	1.55	1.95			
E3	3.04	3.44			
E4	3.21	3.61			
e		1.27 BSC			
e1		7.62 BSC			

Note:

- ① The value of R_{θJA} is measured with the device in a still environment with TA=25°C
- ② Practically the current will be limited by PCB, thermal design and operating temperature. VGS=18V.

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Version	Date	Change
A	2025/5/29	New